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[54] **MANUFACTURE OF SEMICONDUCTOR DEVICE**

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[57] **ABSTRACT**

PURPOSE: To enable correct measurement of the thickness of a film, which is formed on a substrate, by a method wherein a part of a silicon single layer and a part of SOI structure are provided in a same SOI (silicon on insulator) substrate and the silicon single layer part is used as a monitor part.

CONSTITUTION: An oxidation-resisting mask 11a is formed on a wafer periphery part, which is not used for element formation, on the surface of a substrate 10 on one side, and this substrate 10 is oxidized, an oxide film 12 is formed on a part other than the wafer periphery part of the substrate surface and thereafter, the surface of the film 12 is flattened. Then, a substrate 13 on the other side is laminated on the flattened surface and the surface on the opposite side to the laminated surface of the substrate 13 is ground. A part of a silicon single layer and a part of a SOI structure are provided in the same SOI substrate and the silicon single layer part is used as a monitor part. Accordingly, an oxide film does not exist under a film to be measured at the wafer periphery part. Thereby, the thickness of the film to be measured can be measured easily and correctly by an existing measuring device by using the wafer periphery part as a film thickness measuring part.

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